

Description

The VST12N048 uses **Super Trench** technology that is uniquely optimized to provide the most efficient high frequency switching performance. Both conduction and switching power losses are minimized due to an extremely low combination of $R_{\text{DS(ON)}}$ and Q_g . This device is ideal for high-frequency switching and synchronous rectification.

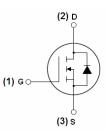
General Features

- $V_{DS} = 120V, I_D = 129A$ $R_{DS(ON)} < 5.3 \text{m}\Omega @ V_{GS} = 10V$
- Excellent gate charge x R_{DS(on)} product
- Very low on-resistance R_{DS(on)}
- 175 °C operating temperature
- Pb-free lead plating
- 100% UIS tested

Application

- DC/DC Converter
- Ideal for high-frequency switching and synchronous rectification





Schematic Diagram

Package Marking and Ordering Information

Device Marking	Device	Device Package	Reel Size	Tape width	Quantity
VST12N048-TC	VST12N048	TO-220C	-	-	-

Absolute Maximum Ratings (T_c=25℃unless otherwise noted)

Parameter	Symbol	Limit	Unit	
Drain-Source Voltage	V _{DS}	120	V	
Gate-Source Voltage	V _G s	±20	V	
Drain Current-Continuous	I _D	129	А	
Drain Current-Continuous(T _C =100℃)	I _D (100℃)	92	А	
Pulsed Drain Current	I _{DM}	480	А	
Maximum Power Dissipation	P _D	185	W	
Derating factor		1.3	W/℃	
Single pulse avalanche energy (Note 5)	E _{AS}	1000	mJ	
Operating Junction and Storage Temperature Range	T_{J}, T_{STG}	-55 To 175	$^{\circ}$ C	



Shenzhen VSEEI Semiconductor Co., Ltd

Thermal Characteristic

Thermal Resistance,Junction-to-Case ^(Note 2)	Rejc	0.8	°C/W	
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Electrical Characteristics (T_C=25°C unless otherwise noted)

Parameter	Symbol	Condition	Min	Тур	Max	Unit
Off Characteristics			•			
Drain-Source Breakdown Voltage	BV _{DSS}	V _{GS} =0V I _D =250μA	120		-	V
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} =120V,V _{GS} =0V	-	-	1	μΑ
Gate-Body Leakage Current	I _{GSS}	V _{GS} =±20V,V _{DS} =0V	-	-	±100	nA
On Characteristics (Note 3)	<u> </u>					
Gate Threshold Voltage	$V_{GS(th)}$	$V_{DS}=V_{GS},I_{D}=250\mu A$	2.5	3.3	4.5	V
Drain-Source On-State Resistance	R _{DS(ON)}	V _{GS} =10V, I _D =60A	-	4.8	5.3	mΩ
Forward Transconductance	g _{FS}	V _{DS} =10V,I _D =60A	60	-	-	S
Dynamic Characteristics (Note4)			1			
Input Capacitance	C _{lss}		-	5600	-	PF
Output Capacitance	C _{oss}	$V_{DS}=50V, V_{GS}=0V,$	-	641	-	PF
Reverse Transfer Capacitance	C _{rss}	F=1.0MHz	-	28	-	PF
Switching Characteristics (Note 4)	<u> </u>					
Turn-on Delay Time	t _{d(on)}	V_{DD} =60V, I_{D} =60A V_{GS} =10V, R_{G} =4.7 Ω	-	16	-	nS
Turn-on Rise Time	t _r		-	67	-	nS
Turn-Off Delay Time	t _{d(off)}		-	45	-	nS
Turn-Off Fall Time	t _f		-	14	-	nS
Total Gate Charge	Qg	V 00VI 00A	-	84.7		nC
Gate-Source Charge	Q _{gs}	$V_{DS}=60V,I_{D}=60A,$	-	30.6		nC
Gate-Drain Charge	Q_{gd}	V _{GS} =10V	-	18.3		nC
Drain-Source Diode Characteristics			1			
Diode Forward Voltage (Note 3)	V _{SD}	V _{GS} =0V,I _S =129A	-		1.2	V
Diode Forward Current (Note 2)	Is		-	-	129	Α
Reverse Recovery Time	t _{rr}	$T_J = 25^{\circ}C, I_F = I_S$	-	60		nS
Reverse Recovery Charge	Qrr	$di/dt = 100A/\mu s^{(Note3)}$	-	140		nC

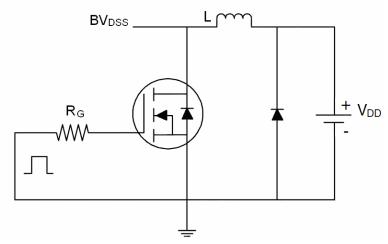
Notes:

- 1. Repetitive Rating: Pulse width limited by maximum junction temperature.
- 2. Surface Mounted on FR4 Board, $t \leq 10 \; \text{sec.}$
- 3. Pulse Test: Pulse Width \leq 300 μ s, Duty Cycle \leq 2%.
- 4. Guaranteed by design, not subject to production
- 5. EAS condition : Tj=25 $^{\circ}\text{C}$,V_DD=50V,V_G=10V,L=0.5mH,Rg=25 Ω

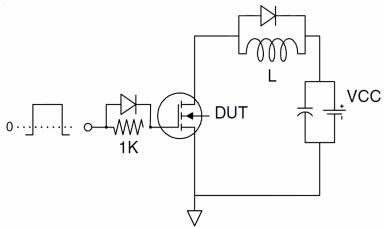


Test Circuit

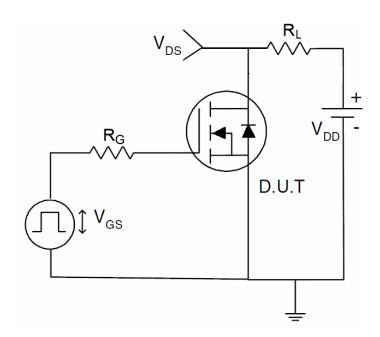
1) E_{AS} test Circuit



2) Gate charge test Circuit



3) Switch Time Test Circuit







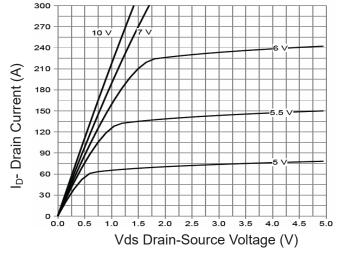


Figure 1 Output Characteristics

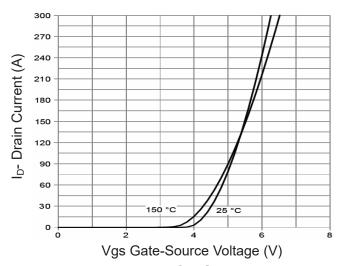


Figure 2 Transfer Characteristics

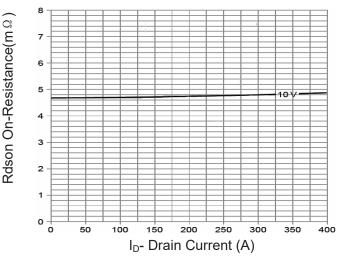


Figure 3 Rdson- Drain Current

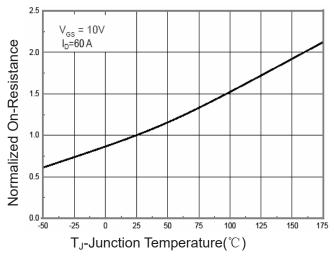


Figure 4 Rdson-JunctionTemperature

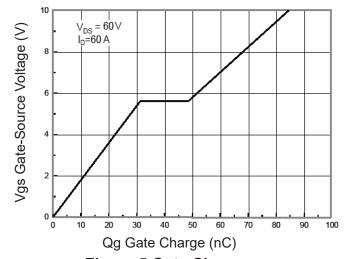


Figure 5 Gate Charge

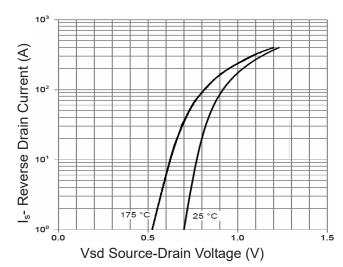


Figure 6 Source- Drain Diode Forward



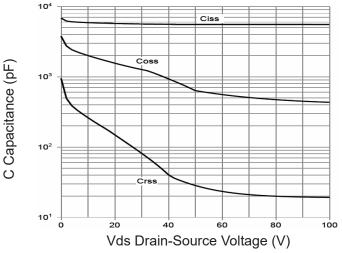
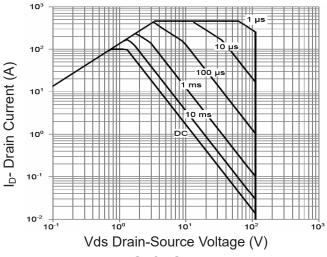


Figure 7 Capacitance vs Vds

 $\label{eq:TJ-Junction} T_{J}\mbox{-Junction Temperature}(^{\circ}\mathbb{C}\,)$ Figure 9 BV $_{DSS}$ vs Junction Temperature



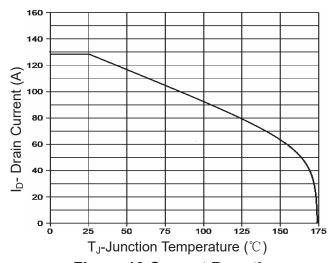
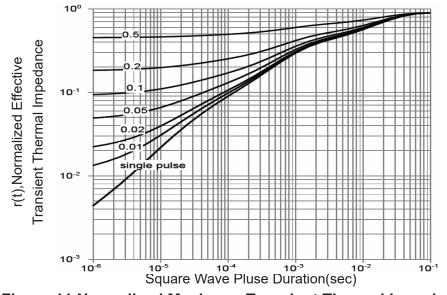


Figure 8 Safe Operation Area

Figure 10 Current De-rating



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Figure 11 Normalized Maximum Transient Thermal Impedance